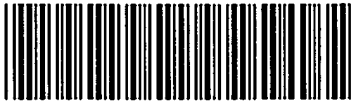


**Search Notes**

Application/Control No.

10/801,706

Examiner

Evan Dzierzynski

Applicant(s)/Patent under  
Reexamination

PAN, WUN-FANG

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	640	7/11/2004	EPD
362	647	7/11/2004	EPD
362	652	7/11/2004	EPD
362	653	7/11/2004	EPD
362	654	7/11/2004	EPD
362	806	7/11/2004	EPD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class and subclass search in east combined with keywords, see attachment	7/11/2004	EPD